

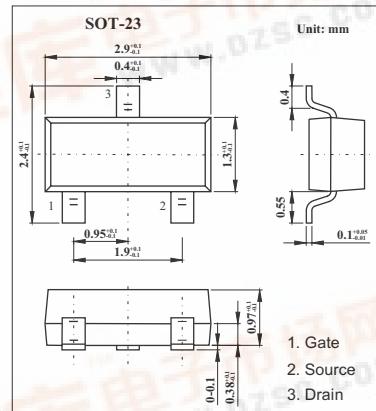
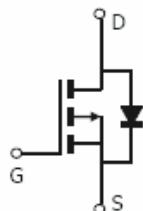
SMD Type

MOSFET

**P-Channel Enhancement Mode  
Field Effect Transistor  
KO3409(AO3409)**

■ Features

- $V_{DS} (V) = -30V$
- $I_D = -2.6 A (V_{GS} = -10V)$
- $R_{DS(ON)} < 130m\Omega (V_{GS} = -10V)$
- $R_{DS(ON)} < 200m\Omega (V_{GS} = -4.5V)$



■ Absolute Maximum Ratings  $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current $T_a=25^\circ C$	$I_D$	-2.6	A
$T_a=70^\circ C$		-2.2	
Pulsed Drain Current	$I_{DM}$	-20	
Power Dissipation $T_a=25^\circ C$	$P_D$	1.4	W
$T_a=70^\circ C$		1	
Thermal Resistance. Junction-to-Ambient	$R_{thJA}$	100	$^\circ C/W$
Thermal Resistance. Junction-to-Case	$R_{thJC}$	63	$^\circ C/W$
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ C$

**KO3409(AO3409)**■ Electrical Characteristics  $T_a = 25^\circ\text{C}$ 

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{DSS}$	$I_D=250 \mu\text{A}, V_{GS}=0\text{V}$	-30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$			-1	$\mu\text{A}$
		$V_{DS}=-24\text{V}, V_{GS}=0\text{V}, T_J=55^\circ\text{C}$			-5	
Gate-Body leakage current	$I_{GSS}$	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS}=V_{GS}, I_D=250 \mu\text{A}$	-1	-1.9	-3	V
Static Drain-Source On-Resistance	$r_{DS(\text{ON})}$	$V_{GS}=-10\text{V}, I_D=-2.6\text{A}$		97	130	$\text{m}\Omega$
		$V_{GS}=-10\text{V}, I_D=-2.6\text{A}, T_J=125^\circ\text{C}$		135	150	
		$V_{GS}=-4.5\text{V}, I_D=-2\text{A}$		166	200	
On state drain current	$I_{D(\text{ON})}$	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-5			A
Forward Transconductance	$g_{fs}$	$V_{DS}=-5\text{V}, I_D=-5\text{A}$	3	3.8		S
Input Capacitance	$C_{iss}$	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		302	370	pF
Output Capacitance	$C_{oss}$			50.3		pF
Reverse Transfer Capacitance	$C_{rss}$			37.8		pF
Gate resistance	$R_g$	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		12	18	$\Omega$
Total Gate Charge (10V)	$Q_g$	$V_{GS}=-4.5\text{V}, V_{DS}=-15\text{V}, I_D=-2.6\text{A}$		6.8	9	nC
Total Gate Charge (4.5V)				2.4		nC
Gate Source Charge	$Q_{gs}$			1.6		nC
Gate Drain Charge	$Q_{gd}$			0.95		nC
Turn-On DelayTime	$t_{D(\text{on})}$	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=5.8\Omega, R_{GEN}=3\Omega$		7.5		ns
Turn-On Rise Time	$t_r$			3.2		ns
Turn-Off DelayTime	$t_{D(\text{off})}$			17		ns
Turn-Off Fall Time	$t_f$			6.8		ns
Body Diode Reverse Recovery Time	$t_{rr}$	$ I_F =-2.6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		16.8	22	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$	$ I_F =-2.6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		10		nC
Maximum Body-Diode Continuous Current	$I_s$				-2	A
Diode Forward Voltage	$V_{SD}$	$I_s=-1\text{A}, V_{GS}=0\text{V}$		-0.82	-1	V

\* Repetitive rating, pulse width limited by junction temperature.